Phase Noise Performance Analysis of VCO Circuit

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- HCI degradation model
- 1/f noise model development (n-MOSFETs)
- HCI measurement
- 1/f noise variability measurement (n-MOSFETs)
- Successfully simulated the phase noise degradation

VCO equivalent circuit

Deterioration model generation for SPICE

Deterioration SPICE model library

VCO equivalent circuit

Fresh → After Stress